

Docket No.: N9460.0020/P020  
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

**In re Patent Application of:  
Eiko Nakazawa, et al.**

**Application No.: Not Yet Assigned**

**Filed: Concurrently Herewith**

Art Unit: N/A

For: SAMPLE OBSERVATION METHOD AND  
TRANSMISSION ELECTRON  
MICROSCOPE

Examiner: Not Yet Assigned

## CLAIM FOR PRIORITY

MS Patent Application  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

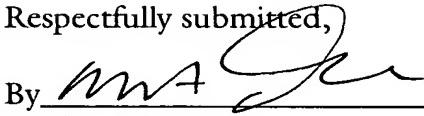
Applicant hereby claims priority under 35 U.S.C. 119 based on the following prior foreign application filed in the following foreign country on the date indicated:

Country	Application No.	Date
Japan	2002-343776	November 27, 2002

In support of this claim, a certified copy of the said original foreign application will be filed shortly.

Dated: November 25, 2003

Respectfully submitted,

By 

Mark J. Thronson

Registration No.: 33,082

DICKSTEIN SHAPIRO MORIN &  
OSHINSKY LLP  
2101 L Street NW  
Washington, DC 20037-1526  
(202) 785-9700  
Attorney for Applicant